

Notice of References Cited	Application/Control No. 10/735,210	Applicant(s)/Patent Under Reexamination TAKAGI, KAZUHISA	
	Examiner John D. Lee <i>John D. Lee</i>	Art Unit 2874	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,515,793	02-2003	Edagawa et al.	359/326
*	B	US-6,646,784	11-2003	Leuthold, Juerg	359/332
	C	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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